- Members of the Texas Instruments
   Widebus™ Family
- Universal Bus Transceiver (UBT™)
   Combines D-Type Latches and D-Type
   Flip-Flops for Operation in Transparent,
   Latched, Clocked, or Clock-Enabled Mode
- Translate Between GTL/GTL+ Signal Levels and LVTTL Logic Levels
- Support Mixed-Mode (3.3-V and 5-V) Signal Operation on A-Port and Control Inputs
- B-Port Transition Time Optimized for Distributed Backplane Loads
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation

- Bus Hold on A-Port Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Distributed V<sub>CC</sub> and GND-Pin Configuration Minimizes High-Speed Switching Noise
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Ceramic Flat (WD) Packages

#### description

The 'GTL16612A devices are 18-bit universal bus transceivers (UBT) that provide LVTTL-to-GTL+ and GTL+-to-LVTTL signal-level translation. They allow for transparent, latched, clocked, or clock-enabled modes of data transfer. These devices provide a high-speed interface between cards operating at LVTTL logic levels and backplanes operating at GTL+ signal levels. High-speed (about two times faster than standard LVTTL or TTL) backplane operation is a direct result of the reduced output swing (<1 V), reduced input threshold levels, and output edge control (OEC™). Improved GTL+ OEC circuits minimize bus settling time and have been designed and tested using several backplane models.

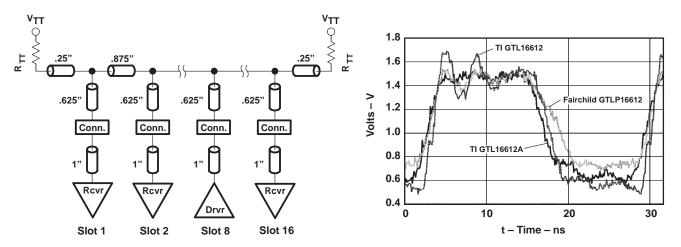


Figure 1. Test Backplane Model With Output Waveform Results



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#### description (continued)

Figure 1 shows actual device output waveforms using a synchronous clock at 75 MHz. The test backplane is a 16-slot, 14-inch board with loaded impedance of  $33\,\Omega$ .  $V_{TT}$  is 1.5 V,  $V_{REF}$  is 1 V, and  $R_{TT}$  pullup resistor is 50  $\Omega$ . The driver is in slot 8, with receivers in alternate slots 1, 3, 5, 7, 10, 12, 14, and 16. Receiver slot 1 signals are shown. The signal becomes progressively worse as the receiver moves closer to the driver or the spacing between receiver cards is reduced. The clock is independent of the data and the system clock frequency is limited by the backplane flight time to about 80–90 MHz. This frequency can be increased even more (30% to 40%) if the clock is generated and transmitted together with the data off the driver card (source synchronous).

Additional design considerations can be found in Application Information at the end of this data sheet.

These 18-bit universal bus transceivers combine D-type latches and D-type flip-flops to allow data flow in transparent, latched, clocked, and clock-enabled modes. These UBTs can replace any of the functions shown in Table 1.

FUNCTION	8 BIT	9 BIT	10 BIT	16 BIT	18 BIT
Transceiver	'245, '623, '645	'863	'861	'16245, '16623	'16863
Buffer/driver	'241, '244, '541		'827	'16241, '16244, '16541	'16825
Latched transceiver	'543			'16543	'16472
Latch	'373, '573	'843	'841	'16373	'16843
Registered transceiver	'646, '652			'16646, '16652	'16474
Flip-flop	'374, '574		'821	'16374	
Standard UBT					'16500, '16501
Universal bus driver					'16835
Registered transceiver with CLK enable	'2952			'16470, '16952	
Flip-flop with CLK enable	'377	'823			'16823
Standard UBT with CLK enable					'16600, '16601

Table 1. 'GTL16612A UBT Replacement Functions

GTL+ is the Texas Instruments (TI<sup>TM</sup>) derivative of the Gunning transceiver logic (GTL) JEDEC standard JESD 8-3. The AC specification of the 'GTL16612A is given only at the preferred higher noise margin GTL+, but this device can be used at either GTL ( $V_{TT} = 1.2 \text{ V}$  and  $V_{REF} = 0.8 \text{ V}$ ) or GTL+ ( $V_{TT} = 1.5 \text{ V}$  and  $V_{REF} = 1 \text{ V}$ ) signal levels.

The B port normally operates at GTL or GTL+ levels, while the A-port and control inputs are compatible with LVTTL logic levels and are 5-V tolerant. V<sub>RFF</sub> is the reference input voltage for the B port.

To improve signal integrity, the 'GTL16612A B-port output transition time is optimized for distributed backplane loads.

V<sub>CC</sub> (5 V) supplies the internal and GTL circuitry, while V<sub>CC</sub> (3.3 V) supplies the LVTTL output buffers.

Data flow in each direction is controlled by output-enable ( $\overline{OEAB}$  and  $\overline{OEBA}$ ), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. The clock or latch enable can be controlled by the clock-enable ( $\overline{CEAB}$  and  $\overline{CEBA}$ ) inputs. For A-to-B data flow, the devices operate in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if  $\overline{CEAB}$  is low and CLKAB is held at a high or low logic level. If LEAB is low, the A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB if  $\overline{CEAB}$  also is low. When  $\overline{OEAB}$  is low, the outputs are active. When  $\overline{OEAB}$  is high, the outputs are in the high-impedance state. Data flow for B to A is similar to that for A to B, but uses  $\overline{OEBA}$ , LEBA, CLKBA, and  $\overline{CEBA}$ .

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

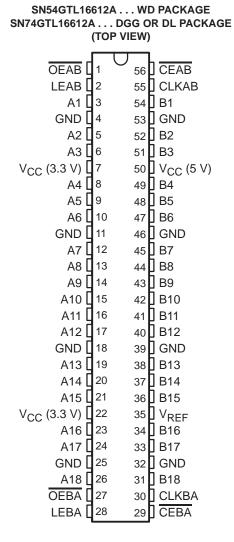


## description (continued)

Active bus-hold circuitry holds unused or undriven LVTTL inputs at a valid logic state. Use of pullup or pulldown resistors with the bus-hold circuitry is not recommended.

These devices are fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down.

The SN54GTL16612A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74GTL16612A is characterized for operation from –40°C to 85°C.

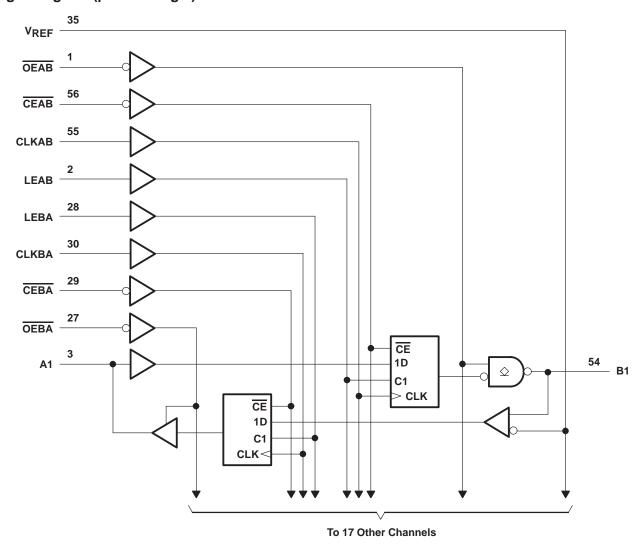


#### **FUNCTION TABLE**†

		INPUTS			OUTPUT	MODE
CEAB	OEAB	LEAB	CLKAB	Α	В	MODE
Х	Н	Χ	Χ	Χ	Z	Isolation
L	L	L	Н	Х	в <sub>0</sub> ‡	Latched storage of A data
L	L	L	L	Χ	В <sub>0</sub> §	Latched Storage of A data
Х	L	Н	Х	L	L	Transparent
Х	L	Н	Χ	Н	н	Transparent
L	L	L	1	L	L	Clasked starons of A data
L	L	L	$\uparrow$	Н	Н	Clocked storage of A data
Н	L	Ĺ	Х	Х	В <sub>0</sub> §	Clock inhibit

<sup>†</sup> A-to-B data flow is shown. B-to-A data flow is similar, but uses  $\overline{\text{OEBA}}$ , LEBA, CLKBA, and  $\overline{\text{CEBA}}$ .

## logic diagram (positive logic)





<sup>&</sup>lt;sup>‡</sup> Output level before the indicated steady-state input conditions were established, provided that CLKAB was high before LEAB went low

<sup>§</sup> Output level before the indicated steady-state input conditions were established

## SN54GTL16612A, SN74GTL16612A 18-BIT LVTTL-TO-GTL+ UNIVERSAL BUS TRANSCEIVERS

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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V <sub>CC</sub> : 3.3 V	0.5 V to 4.6 V
5 V	
Input voltage range, V <sub>I</sub> (see Note 1): A-port and control inputs	–0.5 V to 7 V
B port and V <sub>REF</sub>	
Voltage range applied to any output in the high or power-off state, V <sub>O</sub>	
(see Note 1): A port	–0.5 V to 7 V
B port	
Current into any output in the low state, IO: A port	
B port	
Current into any A-port output in the high state, IO (see Note 2)	64 mA
Continuous current through each V <sub>CC</sub> or GND	
Input clamp current, $I_{IK}$ ( $V_I < 0$ )	
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	
Package thermal impedance, θ <sub>JA</sub> (see Note 3): DGG package	
DL package	
Storage temperature range, T <sub>Sto</sub>	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
  - 2. This current flows only when the output is in the high state and  $V_O > V_{CC}$ .
  - 3. The package thermal impedance is calculated in accordance with JESD 51.

#### recommended operating conditions (see Notes 4 through 6)

			SN54GTL16612A SN74GTL16612A					UNIT		
			MIN	NOM	MAX	MIN	MAX	UNII		
V	Committee	3.3 V	3.15	3.3	3.45	3.15	3.3	3.45	V	
VCC	Supply voltage	5 V	4.75	5	5.25	4.75	5	5.25	V	
V	Termination voltage	GTL	1.14	1.2	1.26	1.14	1.2	1.26	V	
VTT	V     Terrimation voltage	GTL+	1.35	1.5	1.65	1.35	1.5	1.65	v	
V5==	REF Supply voltage	GTL	0.74	0.8	0.87	0.74	0.8	0.87	V	
VREF		GTL+	0.87	1	1.1	0.87	1	1.1	v	
٧,	Input voltage	B port		Ty.	VTT			$V_{TT}$	V	
VI		Except B port		14	5.5			5.5		
V	High-level input voltage	B port	V <sub>REF</sub> +50 m\	1 0		V <sub>REF</sub> +50 mV			V	
VIH		Except B port	2	Ç		2			v	
VIL	Low-level	B port		Ž V	REF-50 mV		\	/ <sub>REF</sub> -50 mV	V	
۷IL	input voltage	Except B port		Q.	8.0			0.8	v	
Ι <sub>ΙΚ</sub>	Input clamp current				-18			-18	mA	
lOH	High-level output current	A port			-32			-32	mA	
1	Low-level output current	A port			64			64	A	
lOL		B port			34			34	mA	
T <sub>A</sub>	Operating free-air ter	mperature	-55		125	-40		85	°C	

NOTES: 4. All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

- 5. Normal connection sequence is GND first,  $V_{CC} = 5 \text{ V}$  second, and  $V_{CC} = 3.3 \text{ V}$ , I/O, control inputs,  $V_{TT}$ , and  $V_{REF}$  (any order) last.
- V<sub>TT</sub> and R<sub>TT</sub> can be adjusted to accommodate backplane impedances as long as they do not exceed the DC absolute I<sub>OL</sub> ratings. Similarly, V<sub>REF</sub> can be adjusted to optimize noise margins, but normally is 2/3 V<sub>TT</sub>.



## SN54GTL16612A, SN74GTL16612A 18-BIT LVTTL-TO-GTL+ UNIVERSAL BUS TRANSCEIVERS

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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAB	METER	TEST CONDITIONS		SN540	TL1661	2A	SN740	STL1661	2A	LINIT	
PARAI	METER	TEST CONDIT		MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT	
VIK		V <sub>CC</sub> (3.3 V) = 3.15 V, V <sub>CC</sub> (5 V) = 4.75 V	I <sub>I</sub> = -18 mA			-1.2			-1.2	V	
		V <sub>CC</sub> (3.3 V) = 3.15 V to 3.45 V, V <sub>CC</sub> (5 V) = 4.75 V to 5.25 V	I <sub>OH</sub> = -100 μA	V <sub>CC</sub> (3.3	V)-0.2		V <sub>CC</sub> (3.3 V)–0.2				
VOH	A port	V <sub>CC</sub> (3.3 V) = 3.15 V,	I <sub>OH</sub> = -8 mA	2.4			2.4			V	
		V <sub>CC</sub> (5 V) = 4.75 V	I <sub>OH</sub> = -32 mA	2			2				
			I <sub>OL</sub> = 100 μA			0.2			0.2		
	A port	$V_{CC}$ (3.3 V) = 3.15 V,	I <sub>OL</sub> = 16 mA			0.4			0.4		
VOL	A port	V <sub>CC</sub> (5 V) = 4.75 V	I <sub>OL</sub> = 32 mA			0.5			0.5	V	
		I <sub>OL</sub> = 64 mA				0.6			0.55		
	B port	$V_{CC}$ (3.3 V) = 3.15 V, $V_{CC}$ (5 V)	= 4.75 V, I <sub>OL</sub> = 34 mA			0.65			0.65		
	Control inputs	V <sub>CC</sub> (3.3 V) = 0 or 3.45 V, V <sub>CC</sub> (5 V) = 0 or 5.25 V	V <sub>I</sub> = 5.5 V			10			10		
		V <sub>CC</sub> (3.3 V) = 3.45 V, V <sub>CC</sub> (5 V) = 5.25 V	V <sub>I</sub> = 5.5 V			1000			20		
l <sub>l</sub>	A port		V <sub>I</sub> = V <sub>CC</sub> (3.3 V)			1			1	μΑ	
ļ ·	'		V <sub>I</sub> = 0		1,0	-30			-30		
	B port	V <sub>CC</sub> (3.3 V) = 3.45 V,	$V_{I} = V_{CC} (3.3 \text{ V})$		N	5			5		
	в роп	V <sub>CC</sub> (5 V) = 5.25 V	V <sub>I</sub> = 0		2	-5	<b>-5 -5</b>				
l <sub>off</sub>	•	$V_{CC} = 0$ ,	$V_{I}$ or $V_{O} = 0$ to 4.5 V		7	1000			100	μΑ	
		V <sub>CC</sub> (3.3 V) = 3.15 V, V <sub>CC</sub> (5 V) = 4.75 V	V <sub>I</sub> = 0.8 V	75	)		75				
I <sub>I</sub> (hold)	A port		V <sub>I</sub> = 2 V	-75			-75			μΑ	
			$V_{I} = 0 \text{ to } V_{CC}(3.3 \text{ V})^{\ddagger}$	Q		±500			±500		
lozh	A port	V <sub>CC</sub> (3.3 V) = 3.45 V, V <sub>CC</sub> (5 V) = 5.25 V	V <sub>O</sub> = V <sub>CC</sub> (3.3 V)			1			1	μА	
	B port	$V_{CC}$ (3.3 V) = 3.45 V, $V_{CC}$ (5 V)	= 5.25 V, V <sub>O</sub> = 1.5 V			10			10		
lo=:	A port	$V_{CC}$ (3.3 V) = 3.45 V, $V_{CC}$ (5 V)	= 5.25 V, V <sub>O</sub> = 0			-1			-1	μА	
IOZL	B port	V <sub>CC</sub> (3.3 V) = 3.45 V, V <sub>CC</sub> (5 V)	= 5.25 V, V <sub>O</sub> = 0.65 V			-10			-10	μΑ	
		$V_{CC}$ (3.3 V) = 3.45 V,	Outputs high			1			1		
(3.3 V)	A or B port	$V_{CC}$ (5 V) = 5.25 V, $I_{O}$ = 0, $V_{I}$ = $V_{CC}$ (3.3 V) or GND§,	Outputs low			5			5	mA	
(3.3 V)	Port	$V_1 = V_{TT}$ or GND¶	Outputs disabled			1			1		
		V <sub>CC</sub> (3.3 V) = 3.45 V,	Outputs high			120			120		
ICC	A or B	$V_{CC}$ (5 V) = 5.25 V, $I_{O}$ = 0,	Outputs low			120			120	mA	
(5 V)	port	$V_I = V_{CC}$ (3.3 V) or GND\$, $V_I = V_{TT}$ or GND¶	Outputs disabled			120			120		
Δl <sub>CC</sub> (3	.3 V)#	V <sub>CC</sub> (3.3 V) = 3.45 V, V <sub>CC</sub> (5 V) One A-port or control input at 2.7 Other A-port or control inputs at V	= 5.25 V, V,			1			1	mA	
Ci	Control inputs	V <sub>I</sub> = 3.15 V or 0			4	12		4		pF	
Cta	A port	$V_0 = 3.15 \text{ V or } 0$			8.5	18		8.5		pF	
C <sub>io</sub>	B port	V <sub>O</sub> = 1.5 V or 0				10		8		l ht	

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC}$  (3.3 V) = 3.3 V,  $V_{CC}$  (5 V) = 5 V,  $T_A$  = 25°C.



<sup>&</sup>lt;sup>‡</sup> This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

 $<sup>\</sup>$  This is the V<sub>I</sub> for A-port or control inputs.

<sup>¶</sup> This is the V<sub>I</sub> for B port.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature, $V_{TT}$ = 1.5 V and $V_{REF}$ = 1 V for GTL+ (unless otherwise noted) (see Figure 2)

			SN54GTL1	6612A	SN74GTL1	16612A	UNIT
			MIN	MAX	MIN	MAX	UNII
fclock	Clock frequency			85		85	MHz
	Pulse duration	LEAB or LEBA high	3.3		3.3		ns
t <sub>W</sub>	Pulse duration	CLKAB or CLKBA high or low	5.7		5.7		115
		A before CLKAB↑	1		1		
	Setup time	B before CLKBA↑	2.7	Z,	1.8		ns
		A before LEAB↓	1.7	i.	0.5		
t <sub>su</sub>		B before LEBA↓	1.2	5	1.2		
		CEAB before CLKAB↑	1.3		1.2		
		CEBA before CLKBA↑	1.8		1.4		
		A after CLKAB↑	3.2		1.9		
		B after CLKBA↑	4.3		0.5		
<b>.</b> .	I laid time	A after LEAB↓	3.2		2.7		
t <sub>h</sub>	Hold time	B after LEBA↓	4.2		3.5		ns
		CEAB after CLKAB↑	2.4		1.2		
		CEBA after CLKBA↑	1.1		1.1		

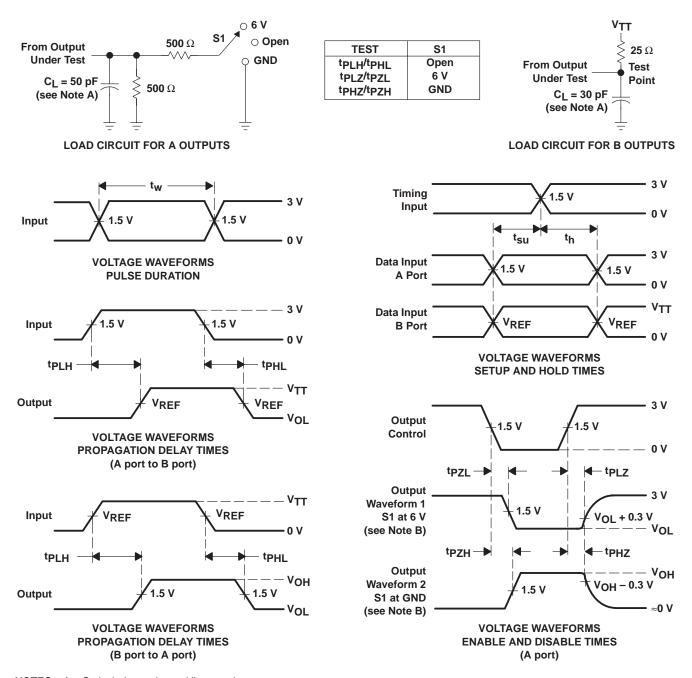
# switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $V_{TT} = 1.5 \text{ V}$ and $V_{REF} = 1 \text{ V}$ for GTL+ (see Figure 2)

DADAMETED	FROM	то	SN54G	TL16612A	SN74GTL16612A			UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN T	YP† MAX	MIN	TYP <sup>†</sup>	MAX	UNII
f <sub>max</sub>			85		85			MHz
<sup>t</sup> PLH	А	В	2	7.3	2.5		6.9	ns
<sup>t</sup> PHL	^	В	2.2	7.4	2.5		6.9	115
<sup>t</sup> PLH	LEAB	В	2.2	7.5	3.2		7.3	ns
<sup>t</sup> PHL	LLAB	В	2.3	7.9	3.2		7.3	115
<sup>t</sup> PLH	CLKAB	В	2.1	8	3.4		7.8	ns
<sup>t</sup> PHL	CLNAD	Ь	2.5	7.9	3.4	3.4		8
t <sub>en</sub>	<del>OEAB</del>	В	1.8	7.4	2.8		7	ns
<sup>t</sup> dis	OEAB	ь	1.8	7	2.8		7	113
t <sub>r</sub>	Transition time, B ou	utputs (20% to 80%)		2.6		2.6		ns
t <sub>f</sub>	Transition time, B ou	utputs (80% to 20%)	2	2.6		2.6		ns
<sup>t</sup> PLH	В	А	1.4	6.3	1.5		5.7	
<sup>t</sup> PHL		A	1.3	6.2	1.5		5.7	ns
<sup>t</sup> PLH	LEBA	А	1.5	6.1	1.8		5.7	ns
<sup>t</sup> PHL	LEBA	A	1	6	1.8		5.7	115
<sup>t</sup> PLH	CLKDA	Δ.	1.8	5.8	2.3		5.5	
<sup>t</sup> PHL	CLKBA	А	2	5.9	2.3		5.5	ns
t <sub>en</sub>	OEBA	^	0.5	6.2	1.8		6.1	nc
<sup>t</sup> dis	] VEDA	А	1.3	6.6	1.8		6.1	ns

 $<sup>\</sup>dagger$  All typical values are at V<sub>CC</sub> (3.3 V) = 3.3 V, V<sub>CC</sub> (5 V) = 5 V, T<sub>A</sub> = 25°C.



#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A.  $C_L$  includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_{\Omega} = 50 \Omega$ ,  $t_r \leq 2.5 \text{ ns.}$
  - D. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuits and Voltage Waveforms



#### **APPLICATION INFORMATION**

### **GTL** background information

GTL was approved as JEDEC standard JESD 8-3 in 1993 and originally was created as a reduced-swing I/O driver technology to support high-speed buses and backplanes. The GTL bus is designed to work with low voltage swings. The input buffer works like an analog comparator rather than like an inverter, which allows the GTL inputs to switch quickly without needing to be driven rail to rail. GTL drivers were designed to pull a 1.2-V signal down to 0.4 V when switched on. This, however, placed the reference voltage for the input comparator at 0.8 V, which made it susceptible to ground-bounce noise. A variant of GTL, called GTL+, is being used to address this noise-margin concern. The GTL+ termination voltage is raised to 1.5 V, with the driver pulling down to a VOI of 0.5 V. This moved the reference voltage to 1 V and out of the range of most ground bounces.

TI GTL devices operate at, and are specified for, both GTL and the improved-noise-margin GTL+ standard. However, the 'GTL16612A devices deviate from this history. They are designed with slow rising and falling edges, to offer significant system frequency improvement in heavily loaded backplanes. They are AC specified only at GTL+ because most applications are moving to this improved-noise-margin standard; they operate at either GTL or GTL+.

Devices named GTL or GTLP indicate reduced voltage-swing operation at a  $V_{TT}$  of 1.2 V (GTL standard) or 1.5 V (improved-noise-margin GTL+ standard). Fast-edge GTL devices are best for point-to-point or lower-frequency backplanes. Slow-edge GTL devices extend backplane operations to cover even higher frequencies.

#### input characteristics

The input characteristics are identical on both A and B ports. Both ports are very high impedance and have an input diode to provide protection against high negative-voltage spikes. The input diode conducts and prevents more sensitive components from being destroyed as the result of electrostatic discharges or line reflections.

#### **GTL** output characteristics

The principle of the GTL bus is based on open-drain drivers, as shown in Figure 3.

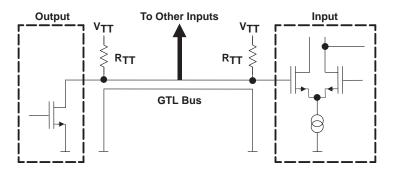


Figure 3. GTL Bus: An Open-Drain Bus

The devices actively drive the bus low, whereas, the termination voltage source,  $V_{TT}$  pulls it high. Only the pullup resistor ( $R_{TT}$ ), which usually is of a low resistance, limits the current. The pullup resistor value should match the fully loaded backplane impedance, not the trace impedance, to provide an optimum termination of the bus and avoid line reflections. The resistance of the GTL output is in the range of a few ohms. However, in the high state, the output transistor is in the high-impedance state.  $R_{TT}$  needs to be greater than 25  $\Omega$  at GTL+ signal levels, not to exceed the 'GTL16612A absolute maximum output current of 80 mA, and should be greater than 50  $\Omega$  at GTL+ signal levels, not to exceed the recommended output current limit of 34 mA.

#### APPLICATION INFORMATION

#### **OEC**

The 'GTL16612A GTL output consists of an improved edge-control circuit that provides optimized rise and fall times, typically 2.6 ns (20% to 80%), for backplanes under various loading conditions.

Using the definition of slew rate  $\Delta t/\Delta v = t_r$  or  $t_f/(V_{OH} - V_{OL})$ , the slew rate of the device typically is 5 ns/V. As a comparison, these values are significantly more than those of previous GTL or standard TTL devices, which are usually about 1 ns/V, or less.

## termination voltage, V<sub>TT</sub>

The termination voltage ( $V_{TT}$ ) should be derived from a voltage regulator that can provide up to 50-mA current per signal line. There are various voltage regulators that meet these requirements. Depending on the application, the regulators should be mounted either directly on the backplane or on the daughter boards. It is highly recommended that ceramic bypass capacitors be used (due to high impedance) at the termination resistors because several signal lines may be switching simultaneously, causing considerable current fluctuations at the termination voltage.

#### reference voltage, V<sub>REF</sub>

The GTL reference voltage ( $V_{REF}$ ) can be derived using a simple voltage divider between  $V_{TT}$  and GND with an R-to-2R ratio and a bypass capacitor (0.01–0.1  $\mu$ F) as close to the  $V_{REF}$  terminal as possible (see Figure 4). Generating  $V_{REF}$  from  $V_{TT}$  ensures the maximum possible signal-to-noise ratio (SNR) even with an unstable termination voltage. It also is recommended to generate  $V_{REF}$  locally on each plug-in card instead of on the backplane.

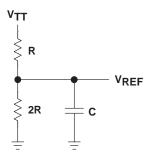


Figure 4. Suggested Connection of V<sub>REF</sub> Terminal

#### partial power down

Device power can be switched off without having to remove the device from the system. This is a partial power down. 'GTL16612A can be used in a partial-power-down application where  $V_{CC} = 0$  because the inputs and outputs are at high impedance and are able to tolerate active bus signals. This is reflected in the  $I_{off}$  parameter, which specifies the maximum input or output leakage current.

#### bus-hold circuit

Bus hold on A-port inputs (LVTTL side) prevents any unused or floating inputs from damaging the device. To change the logic state stored by the bus-hold circuit, a current of about  $250-300\,\mu\text{A}$  must be overridden. There is no bus hold on the B port (GTL side). A bus-hold circuit on the GTL side would defeat the purpose of the open-drain outputs, which take on the high-impedance state to allow the bus to achieve a logic high state via the pullup resistors.



#### APPLICATION INFORMATION

### source-synchronous clock applications

When the clock originates at the driver card and is carried out with the data, the backplane maximum frequency can be achieved. This is possible because the backplane flight time no longer is the limiting factor.

Figure 5 shows results of the 'GTL16612A operating at 100 MHz in a source-synchronous mode.

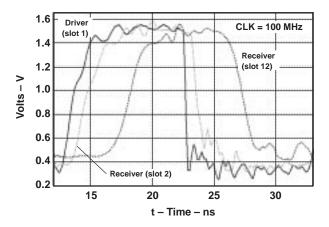


Figure 5. Source-Synchronous Clock

## summary

'GTL16612A devices provide significant benefits when designing high-speed parallel backplanes.

- B port specifically optimized for distributed backplane levels
- Improved B-port GTL edge-control circuitry provides better signal integrity at higher frequencies.
- Reduced power consumption over BTL technology
- Similar to 'LVTH16601, with the B port operating at GTL+ signal levels
- Data throughput is 1.35 Gbit/s at 75-MHz clock speed.
- Provide about two times the data throughput over existing TTL devices, using existing parallel backplane designs

Additional information on GTL devices and backplane design considerations can be found at http://www.ti.com/sc/qtl.

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